S arch Notes



Application/Control No.	Applicant(s)/Patent under R examination	
10/645,863	HELLER ET AL.	
Examiner	Art Unit	
Fric S. De long	1631	

SEARCHED					
Class	Subclass	Date	Examiner		
435	4	1/12/2004	EDJ		
702	19	1/12/2004	EDJ		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
702	27	1/12/2004	EDJ		

SEARCH NOT (INCLUDING SEARCH		
	DATE	EXMR
EAST/WEST, STN, Medline, CAS	1/12/2004	EDJ
Search Terms: mass spectrometry, electrophoresis, microfluidics, disease, phenotype, phenotypic, pattern	1/12/2004	EDJ
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